



780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

GENERAL DESCRIPTION



The ICS84320-01 is a general purpose, dual output Crystal-to-3.3V Differential LVPECL High Frequency Synthesizer and a member of the HiPerClockS™ family of High Performance Clock Solutions from IDT. The ICS84320-01 has a se-

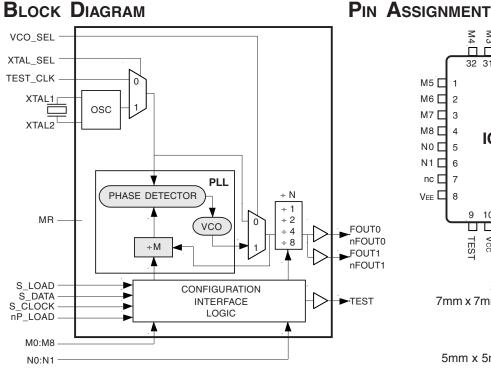
lectable TEST_CLK or crystal inputs. The VCO operates at a frequency range of 620MHz to 780MHz. The VCO frequency is programmed in steps equal to the value of the input reference or crystal frequency. The VCO and output frequency can be programmed using the serial or parallel interfaces to the configuration logic. The low phase noise characteristics of the ICS84320-01 make it an ideal clock source for 10 Gigabit Ethernet, SONET, and Serial Attached SCSI applications.

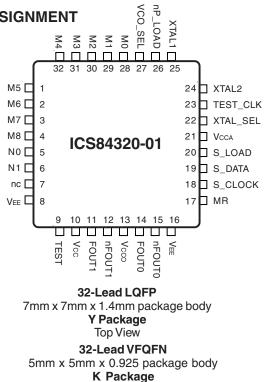
FEATURES

- · Dual differential 3.3V LVPECL outputs
- Selectable crystal oscillator interface or LVCMOS/LVTTL TEST_CLK
- Output frequency range: 77.5MHz to 780MHz
- · Crystal input frequency range: 14MHz to 40MHz
- VCO range: 620MHz to 780MHz
- Parallel or serial interface for programming counter and output dividers
- Duty cycle: 49% 51% (N > 1)
- RMS period jitter: 2ps (typical)
- RMS phase jitter at 155.52MHz, using a 38.88MHz crystal (12kHz to 20MHz): 2.5ps (typical)

Offset	Noise Power
100Hz	90.5 dBc/Hz
1kHz	114.2 dBc/Hz
10kHz	123.6 dBc/Hz
100kHz	128.1 dBc/Hz

- 3.3V supply voltage
- 0°C to 70°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free RoHS (6) packages





Top View

84320AY-01 1 REV. C OCTOBER 22, 2007

780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

FUNCTIONAL DESCRIPTION

NOTE: The functional description that follows describes operation using a 25MHz crystal. Valid PLL loop divider values for different crystal or input frequencies are defined in the Input Frequency Characteristics, Table 5, NOTE 1.

The ICS84320-01 features a fully integrated PLL and therefore requires no external components for setting the loop bandwidth. A fundamental crystal is used as the input to the onchip oscillator. The output of the oscillator is fed into the phase detector. A 25MHz crystal provides a 25MHz phase detector reference frequency. The VCO of the PLL operates over a range of 620MHz to 780MHz. The output of the M divider is also applied to the phase detector.

The phase detector and the M divider force the VCO output frequency to be M times the reference frequency by adjusting the VCO control voltage. Note that for some values of M (either too high or too low), the PLL will not achieve lock. The output of the VCO is scaled by a divider prior to being sent to each of the LVPECL output buffers. The divider provides a 50% output duty cycle.

The programmable features of the ICS84320-01 support two input modes to program the M divider and N output divider. The two input operational modes are parallel and serial. *Figure 1* shows the timing diagram for each mode. In parallel mode, the nP_LOAD input is initially LOW. The data on inputs M0 through M8 and N0 and N1 is passed directly to the M divider and N output divider. On the LOW-to-HIGH transition of the nP_LOAD input, the data is latched and the M divider remains loaded until the next LOW transition on nP_LOAD or until a serial event occurs. As a result, the M and N bits can be hardwired to set the M divider and N output divider to a specific default state that will auto-

matically occur during power-up. The TEST output is LOW when operating in the parallel input mode. The relation-ship between the VCO frequency, the crystal frequency and the M divider is defined as follows:

fVCO = fxtal x M

The M value and the required values of M0 through M8 are shown in Table 3B to program the VCO Frequency Function Table. Valid M values for which the PLL will achieve lock for a 25MHz reference are defined as $25 \le M \le 31$. The frequency out is defined as follows:

$$FOUT = \frac{fVCO}{N} = fxtal \times \frac{M}{N}$$

Serial operation occurs when nP_LOAD is HIGH and S_LOAD is LOW. The shift register is loaded by sampling the S_DATA bits with the rising edge of S_CLOCK. The contents of the shift register are loaded into the M divider and N output divider when S_LOAD transitions from LOW-to-HIGH. The M divide and N output divide values are latched on the HIGH-to-LOW transition of S_LOAD. If S_LOAD is held HIGH, data at the S_DATA input is passed directly to the M divider and N output divider on each rising edge of S_CLOCK. The serial mode can be used to program the M and N bits and test bits T1 and T0. The internal registers T0 and T1 determine the state of the TEST output as follows:

<u>T1</u>	<u>T0</u>	TEST Output
0	0	LOW
0	1	S_Data, Shift Register Input
1	0	Output of M divider
1	1	CMOS Fout

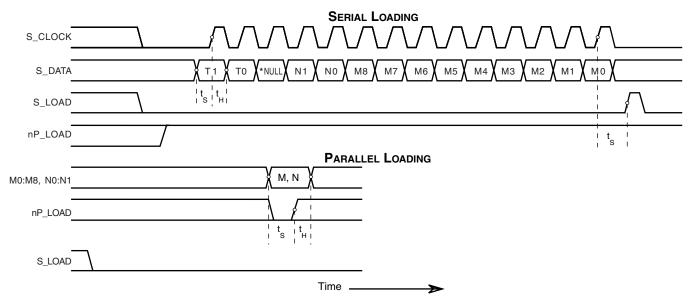


FIGURE 1. PARALLEL & SERIAL LOAD OPERATIONS

TABLE 1. PIN DESCRIPTIONS

Number	Name	Ty	уре	Description
1	M5 M6, M7, M8,	Input	Pullup	M divider inputs. Data latched on LOW-to-HIGH transition of
2, 3, 4, 28, 29, 30, 31, 32	M0, M1, M2, M3, M4	Input	Pulldown	nP_LOAD input. LVCMOS / LVTTL interface levels.
5, 6	N0, N1	Input	Pulldown	Determines output divider value as defined in Table 3C, Function Table. LVCMOS / LVTTL interface levels.
7	nc	Unused		No connect.
8, 16	V_{EE}	Power		Negative supply pins.
9	TEST	Output		Test output which is ACTIVE in the serial mode of operation. Output driven LOW in parallel mode. LVCMOS/LVTTL interface levels.
10	V _{cc}	Power		Core supply pin.
11, 12	FOUT1, nFOUT1	Output		Differential output for the synthesizer. LVPECL interface levels.
13	V _{cco}	Power		Output supply pin.
14, 15	FOUT0, nFOUT0	Output		Differential output for the synthesizer. LVPECL interface levels.
17	MR	Input	Pulldown	Active High Master Reset. When logic HIGH, forces the internal dividers are reset causing the true outputs FOUTx to go low and the inverted outputs nFOUTx to go high. When logic LOW, the internal dividers and the outputs are enabled. Assertion of MR does not affect loaded M, N, and T values. LVCMOS / LVTTL interface levels.
18	S_CLOCK	Input	Pulldown	Clocks in serial data present at S_DATA input into the shift register on the rising edge of S_CLOCK. LVCMOS/LVTTL interface levels.
19	S_DATA	Input	Pulldown	Shift register serial input. Data sampled on the rising edge of S_CLOCK. LVCMOS/LVTTL interface levels.
20	S_LOAD	Input	Pulldown	Controls transition of data from shift register into the dividers. LVCMOS / LVTTL interface levels.
21	V_{CCA}	Power		Analog supply pin.
22	XTAL_SEL	Input	Pullup	Selects between crystal or test inputs as the PLL reference source. Selects XTAL inputs when HIGH. Selects TEST_CLK when LOW. LVCMOS / LVTTL interface levels.
23	TEST_CLK	Input	Pulldown	Test clock input. LVCMOS / LVTTL interface levels.
24, 25	XTAL2, XTAL1	Input		Crystal oscillator interface. XTAL1 is the input. XTAL2 is the output.
26	nP_LOAD	Input	Pulldown	Parallel load input. Determines when data present at M8:M0 is loaded into M divider, and when data present at N1:N0 sets the N output divider value. LVCMOS / LVTTL interface levels.
27	VCO_SEL	Input	Pullup	Determines whether synthesizer is in PLL or bypass mode. LVCMOS / LVTTL interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

TABLE 2. PIN CHARACTERISTICS

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		рF
R _{PULLUP}	Input Pullup Resistor			51		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ

TABLE 3A. PARALLEL AND SERIAL MODE FUNCTION TABLE

			In	puts			Conditions
MR	nP_LOAD	М	N	S_LOAD	S_CLOCK	S_DATA	Conditions
Н	Х	Χ	Х	Х	X	Х	Reset. Forces outputs LOW.
L	L	Data	Data	Х	Х	Х	Data on M and N inputs passed directly to the M divider and N output divider. TEST output forced LOW.
L	1	Data	Data	L	Х	Х	Data is latched into input registers and remains loaded until next LOW transition or until a serial event occurs.
L	Н	Х	Х	L	1	Data	Serial input mode. Shift register is loaded with data on S_DATA on each rising edge of S_CLOCK.
L	Н	Х	Х	↑	L	Data	Contents of the shift register are passed to the M divider and N output divider.
L	Н	Х	Х	\downarrow	L	Data	M divider and N output divider values are latched.
L	Н	Х	Х	L	Х	Х	Parallel or serial input do not affect shift registers.
L	Н	Х	Х	Н	1	Data	S_DATA passed directly to M divider as it is clocked.

NOTE: L = LOW H = HIGHX = Don't care

↑ = Rising edge transition ↓= Falling edge transition

TABLE 3B. PROGRAMMABLE VCO FREQUENCY FUNCTION TABLE

VCO Frequency	M Divide	256	128	64	32	16	8	4	2	1
(MHz)	M Divide	M8	M7	М6	M5	M4	М3	M2	M1	МО
625	25	0	0	0	0	1	1	0	0	1
•	•	•	•	•	•	•	•	•	•	•
700	28	0	0	0	0	1	1	1	0	0
•	•	•	•	•	•	•	•	•	•	•
775	31	0	0	0	0	1	1	1	1	1

NOTE 1: These M divide values and the resulting frequencies correspond to crystal or TEST_CLK input frequency of 25MHz.

TABLE 3C. PROGRAMMABLE OUTPUT DIVIDER FUNCTION TABLE

Inp	outs	N Divider Value	Output Freq	uency (MHz)
N1	N0	N Divider value	Minimum	Maximum
0	0	1	620	780
0	1	2	310	390
1	0	4	155	195
1	1	8	77.5	97.5



780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

ABSOLUTE MAXIMUM RATINGS

Supply Voltage, V_{CC} 4.6V

-0.5V to $V_{\rm CC}$ + 0.5 V Inputs, V

Outputs, V_O (LVCMOS) -0.5V to $V_{CCO} + 0.5V$

Outputs, I_O (LVPECL)

Continuous Current 50mA Surge Current 100mA

Package Thermal Impedance, θ_{JA} 32 Lead LQFP 47.9°C/W (0 lfpm) 34.8°C/W (0 Ifpm) 32 Lead VFQFN -65°C to 150°C Storage Temperature, T_{STG}

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the DC Characteristics or AC Characteristics is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Table 4A. Power Supply DC Characteristics, $V_{CC} = V_{CCA} = V_{CCO} = 3.3V \pm 5\%$, Ta = 0°C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V _{cc}	Core Supply Voltage		3.135	3.3	3.465	V
V _{CCA}	Analog Supply Voltage		V _{cc} - 0.22	3.3	3.465	V
V _{cco}	Output Supply Voltage		3.135	3.3	3.465	V
I _{EE}	Power Supply Current				155	mA
I _{CCA}	Analog Supply Current				22	mA

Table 4B. LVCMOS / LVTTL DC Characteristics, $V_{CC} = V_{CCA} = V_{CCO} = 3.3V \pm 5\%$, Ta = 0°C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V _{IH}	Input High Voltage	VCO_SEL, XTAL_SEL, MR, S_LOAD, nP_LOAD, N0:N1, S_DATA, S_CLOCK, M0:M8		2		V _{cc} + 0.3	V
		TEST_CLK		2		$V_{cc} + 0.3$	V
V _{IL}	Input Low Voltage	VCO_SEL, XTAL_SEL, MR, S_LOAD, nP_LOAD, N0:N1, S_DATA, S_CLOCK, M0:M8		-0.3		0.8	V
		TEST_CLK		-0.3		1.3	V
I _{IH}	Input High Current	M0-M4, M6-M8, N0, N1, MR, S_CLOCK, TEST_CLK, S_DATA, S_LOAD, nP_LOAD	V _{CC} = V _{IN} = 3.465V			150	μΑ
	riigii Gairoiti	M5, XTAL_SEL, VCO_SEL	$V_{CC} = V_{IN} = 3.465V$			5	μΑ
I _{IL}	Input	M0-M4, M6-M8, N0, N1, MR, S_CLOCK, TEST_CLK, S_DATA, S_LOAD, nP_LOAD	$V_{CC} = 3.465V,$ $V_{IN} = 0V$	-5			μΑ
-112	Low Current	M5, XTAL_SEL, VCO_SEL	$V_{CC} = 3.465V,$ $V_{IN} = 0V$	-150			μΑ
V _{OH}	Output High Voltage	TEST; NOTE 1		2.6			V
V _{OL}	Output Low Voltage	TEST; NOTE 1				0.5	V

NOTE 1: Outputs terminated with 50Ω to $V_{cco}/2$.



780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

Table 4C. LVPECL DC Characteristics, $V_{CC} = V_{CCA} = V_{CCO} = 3.3V \pm 5\%$, Ta = 0°C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V _{OH}	Output High Voltage; NOTE 1		V _{cco} - 1.4		V _{cco} - 0.9	V
V _{OL}	Output Low Voltage; NOTE 1		V _{cco} - 2.0		V _{cco} - 1.7	V
V _{SWING}	Peak-to-Peak Output Voltage Swing		0.6		1.0	V

NOTE 1: Outputs terminated with 50 Ω to $\mbox{ V}_{\mbox{\tiny CCO}}$ - 2V. See "Parameter Measurement Information" section, "3.3V Output Load Test Circuit".

Table 5. Input Frequency Characteristics, $V_{CC} = V_{CCA} = V_{CCO} = 3.3V \pm 5\%$, Ta = 0°C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
		TEST_CLK; NOTE 1		14		40	MHz
f _{IN}	Input Frequency	XTAL1, XTAL2; NOTE 1		14		40	MHz
		S_CLOCK				50	MHz

NOTE 1: For the input crystal and TEST_CLK frequency range, the M value must be set for the VCO to operate within the 620MHz to 780MHz range. Using the minimum input frequency of 14MHz, valid values of M are $45 \le M \le 55$. Using the maximum frequency of 40MHz, valid values of M are $16 \le M \le 19$.

TABLE 6. CRYSTAL CHARACTERISTICS

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation		Fı	ındamenta	al	
Frequency		14		40	MHz
Equivalent Series Resistance (ESR)				50	Ω
Shunt Capacitance				7	pF
Drive Level				1	mW

Table 7. AC Characteristics, $V_{CC} = V_{CCA} = V_{CCO} = 3.3V \pm 5\%$, Ta = 0°C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
F _{out}	Output Frequency			77.5		780	MHz
tjit(per)	Period Jitter, RMS; NOTE 1		fOUT > 100MHz		2.0	2.6	ps
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section		155.52MHz, 12kHz - 20MHz		2.5		ps
tsk(o)	Output Skew; NOTE 2, 3					15	ps
t_R/t_F	Output Rise/Fall Time		20% to 80%	150		600	ps
	Setup Time	M, N to nP_LOAD		5			ns
t _s		S_DATA to S_CLOCK		5			ns
		S_CLOCK to S_LOAD		5			ns
	Hold Time	M, N to nP_LOAD		5			ns
t _H		S_DATA to S_CLOCK		5			ns
		S_CLOCK to S_LOAD		5			ns
1 -	Output Duty Cycle		N > 1	49		51	%
odc			fOUT ≤ 625	45		55	%
t _{PW}	Output Pulse Width		f > 625	t _{PERIOD} /2 - 150		$t_{PERIOD}/2 + 150$	ps
t _{LOCK}	PLL Lock Time					1	ms

See Parameter Measurement Information section.

NOTE 1: Jitter performance using XTAL inputs.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at the output differential cross points.

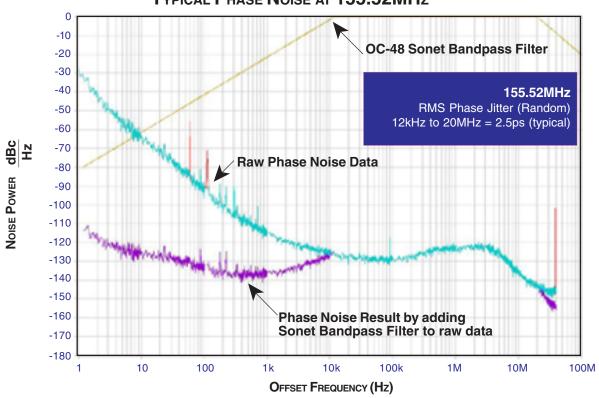
NOTE 3: This parameter is defined in accordance with JEDEC Standard 65.

84320AY01 6 REV.C OCTOBER 22, 2007

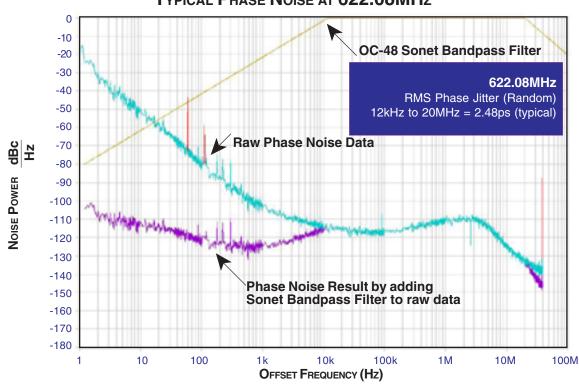


780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

Typical Phase Noise at 155.52MHz

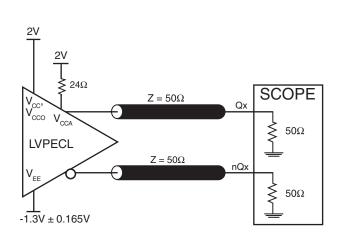


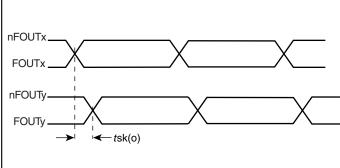
Typical Phase Noise at 622.08MHz





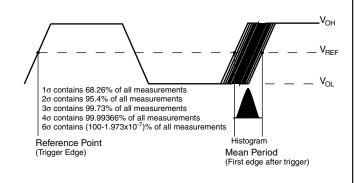
PARAMETER MEASUREMENT INFORMATION

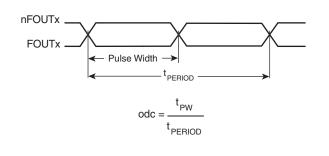




3.3V OUTPUT LOAD AC TEST CIRCUIT

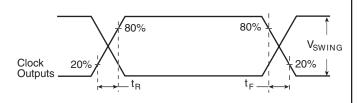
OUTPUT SKEW





PERIOD JITTER

OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD



OUTPUT RISE/FALL TIME

APPLICATION INFORMATION

Power Supply Filtering Techniques

As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. The ICS84320-01 provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL. $V_{\rm CC}, V_{\rm CCA},$ and $V_{\rm CCO}$ should be individually connected to the power supply plane through vias, and bypass capacitors should be used for each pin. To achieve optimum jitter performance, power supply isolation is required. Figure 2 illustrates how a 24Ω resistor along with a $10\mu F$ and a $.01\mu F$ bypass capacitor should be connected to each $V_{\rm CCA}$ pin. The 24Ω resistor can also be replaced by a ferrite bead.

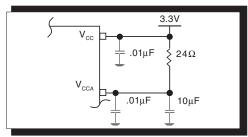


FIGURE 2. POWER SUPPLY FILTERING

RECOMMENDATIONS FOR UNUSED INPUT AND OUTPUT PINS

INPUTS:

CRYSTAL INPUTS

For applications not requiring the use of the crystal oscillator input, both XTAL_IN and XTAL_OUT can be left floating. Though not required, but for additional protection, a $1 \mbox{k}\Omega$ resistor can be tied from XTAL_IN to ground.

TEST_CLK INPUT

For applications not requiring the use of the test clock, it can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from the TEST_CLK to ground.

LVCMOS CONTROL PINS

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A $1k\Omega$ resistor can be used.

OUTPUTS:

LVPECL OUTPUTS

All unused LVPECL outputs can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.

84320AY01 9 REV.C OCTOBER 22, 2007

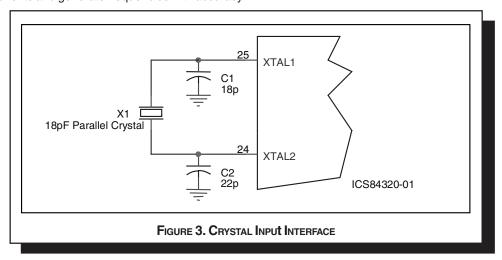


780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

CRYSTAL INPUT INTERFACE

A crystal can be characterized for either series or parallel mode operation. The ICS84320-01 has a built-in crystal oscillator circuit. This interface can accept either a series or parallel crystal without additional components and generate frequencies with accuracy

suitable for most applications. Additional accuracy can be achieved by adding two small capacitors C1 and C2 as shown in *Figure 3*.



LVCMOS TO XTAL INTERFACE

The XTAL_IN input can accept a single-ended LVCMOS signal through an AC coupling capacitor. A general interface diagram is shown in *Figure 4*. The XTAL_OUT pin can be left floating. The input edge rate can be as slow as 10ns. For LVCMOS inputs, it is recommended that the amplitude be reduced from full swing to half swing in order to prevent signal interference with the power rail and to reduce noise. This configuration requires that the output impedance of the driver (Ro) plus the

series resistance (Rs) equals the transmission line impedance. In addition, matched termination at the crystal input will attenuate the signal in half. This can be done in one of two ways. First, R1 and R2 in parallel should equal the transmission line impedance. For most 50Ω applications, R1 and R2 can be 100Ω . This can also be accomplished by removing R1 and making R2 50Ω .

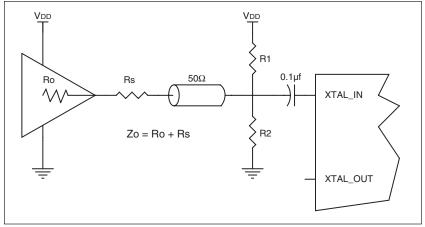


FIGURE 4. GENERAL DIAGRAM FOR LVCMOS DRIVER TO XTAL INPUT INTERFACE



780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

TERMINATION FOR LVPECL OUTPUTS

The clock layout topology shown below is a typical termination for LVPECL outputs. The two different layouts mentioned are recommended only as guidelines.

FOUT and nFOUT are low impedance follower outputs that generate ECL/LVPECL compatible outputs. Therefore, terminating resistors (DC current path to ground) or current sources must be used for functionality. These outputs are designed to drive 50Ω transmission lines. Matched imped-

ance techniques should be used to maximize operating frequency and minimize signal distortion. *Figures 5A and 5B* show two different layouts which are recommended only as guidelines. Other suitable clock layouts may exist and it would be recommended that the board designers simulate to guarantee compatibility across all printed circuit and clock component process variations.

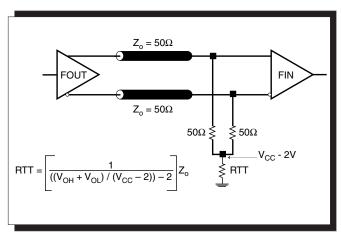


FIGURE 5A. LVPECL OUTPUT TERMINATION

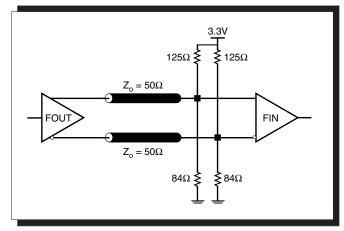


FIGURE 5B. LVPECL OUTPUT TERMINATION



780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

LAYOUT GUIDELINE

The schematic of the ICS84320-01 layout example used in this layout guideline is shown in *Figure 6A*. The ICS84320-01 recommended PCB board layout for this example is shown in *Figure 6B*. This layout example is used as a gen-

eral guideline. The layout in the actual system will depend on the selected component types, the density of the components, the density of the traces, and the stack up of the P.C. board.

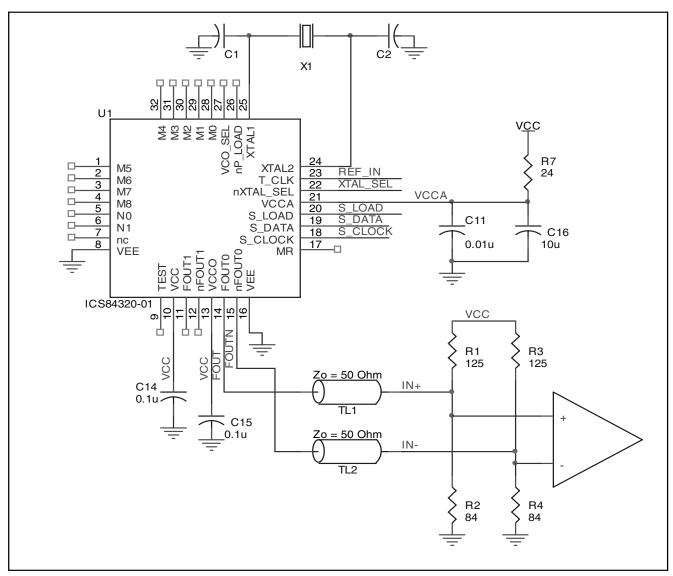


FIGURE 6A. SCHEMATIC OF RECOMMENDED LAYOUT



780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

The following component footprints are used in this layout example:

All the resistors and capacitors are size 0603.

POWER AND GROUNDING

Place the decoupling capacitors C14 and C15, as close as possible to the power pins. If space allows, placement of the decoupling capacitor on the component side is preferred. This can reduce unwanted inductance between the decoupling capacitor and the power pin caused by the via.

Maximize the power and ground pad sizes and number of vias capacitors. This can reduce the inductance between the power and ground planes and the component power and ground pins.

The RC filter consisting of R7, C11, and C16 should be placed as close to the $\rm V_{\rm CCA}$ pin as possible.

CLOCK TRACES AND TERMINATION

Poor signal integrity can degrade the system performance or cause system failure. In synchronous high-speed digital systems, the clock signal is less tolerant to poor signal integrity than other signals. Any ringing on the rising or falling edge or excessive ring back can cause system failure. The shape of the trace and the trace delay might be restricted by the available space on the board and the component location. While routing the traces, the clock signal traces should be routed first and should be locked prior to routing other signal traces.

- The differential 50Ω output traces should have the same length.
- Avoid sharp angles on the clock trace. Sharp angle turns cause the characteristic impedance to change on the transmission lines.
- Keep the clock traces on the same layer. Whenever possible, avoid placing vias on the clock traces. Placement of vias on the traces can affect the trace characteristic impedance and hence degrade signal integrity.
- To prevent cross talk, avoid routing other signal traces in parallel with the clock traces. If running parallel traces is unavoidable, allow a separation of at least three trace widths between the differential clock trace and the other signal trace.
- Make sure no other signal traces are routed between the clock trace pair.
- The matching termination resistors should be located as close to the receiver input pins as possible.

CRYSTAL

The crystal X1 should be located as close as possible to the pins 25 (XTAL1) and 24 (XTAL2). The trace length between the X1 and U1 should be kept to a minimum to avoid unwanted parasitic inductance and capacitance. Other signal traces should not be routed near the crystal traces.

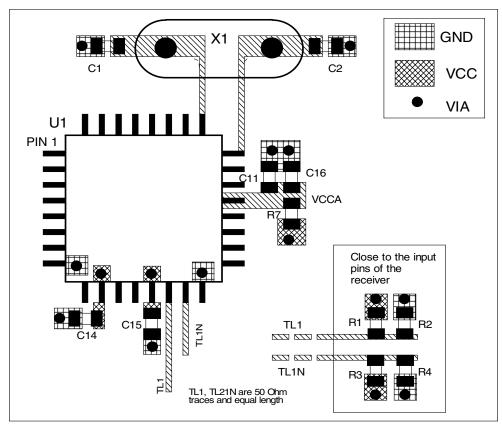


FIGURE 6B. PCB BOARD LAYOUT FOR ICS84320-01



780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

VFQFN EPAD THERMAL RELEASE PATH

In order to maximize both the removal of heat from the package and the electrical performance, a land pattern must be incorporated on the Printed Circuit Board (PCB) within the footprint of the package corresponding to the exposed metal pad or exposed heat slug on the package, as shown in *Figure 7*. The solderable area on the PCB, as defined by the solder mask, should be at least the same size/shape as the exposed pad/slug area on the package to maximize the thermal/electrical performance. Sufficient clearance should be designed on the PCB between the outer edges of the land pattern and the inner edges of pad pattern for the leads to avoid any shorts.

While the land pattern on the PCB provides a means of heat transfer and electrical grounding from the package to the board through a solder joint, thermal vias are necessary to effectively conduct from the surface of the PCB to the ground plane(s). The land pattern must be connected to ground through these vias. The vias act as "heat pipes". The number of vias (i.e.

"heat pipes") are application specific and dependent upon the package power dissipation as well as electrical conductivity requirements. Thus, thermal and electrical analysis and/or testing are recommended to determine the minimum number needed. Maximum thermal and electrical performance is achieved when an array of vias is incorporated in the land pattern. It is recommended to use as many vias connected to ground as possible. It is also recommended that the via diameter should be 12 to 13mils (0.30 to 0.33mm) with 1oz copper via barrel plating. This is desirable to avoid any solder wicking inside the via during the soldering process which may result in voids in solder between the exposed pad/slug and the thermal land. Precautions should be taken to eliminate any solder voids between the exposed heat slug and the land pattern. Note: These recommendations are to be used as a guideline only. For further information, refer to the Application Note on the Surface Mount Assembly of Amkor's Thermally/Electrically Enhance Leadfame Base Package, Amkor Technology.

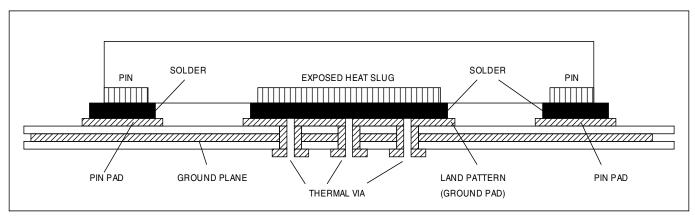


FIGURE 7. P.C. ASSEMBLY FOR EXPOSED PAD THERMAL RELEASE PATH - SIDE VIEW (DRAWING NOT TO SCALE)



780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

POWER CONSIDERATIONS

This section provides information on power dissipation and junction temperature for the ICS84320-01. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the ICS84320-01 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for $V_{CC} = 3.3V + 5\% = 3.465V$, which gives worst case results.

NOTE: Please refer to Section 3 for details on calculating power dissipated in the load.

- Power (core)_{MAX} = V_{CC_MAX} * I_{EE_MAX} = 3.465V * 155mA = 537.08mW
- Power (outputs)_{MAX} = 30mW/Loaded Output pair
 If all outputs are loaded, the total power is 2 * 30mW = 60mW

Total Power $_{MAX}$ (3.465V, with all outputs switching) = 537.1mW + 60mW = 597.1mW

2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS TM devices is 125 $^{\circ}$ C.

The equation for Tj is as follows: Tj = θ_{IA} * Pd_total + T_A

Tj = Junction Temperature

 θ_{14} = Junction-to-Ambient Thermal Resistance

Pd_total = Total Device Power Dissipation (example calculation is in section 1 above)

 T_{Δ} = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming a moderate air flow of 200 linear feet per minute and a multi-layer board, the appropriate value is 42.1°C/W per Table 8A below.

Therefore, Tj for an ambient temperature of 70°C with all outputs switching is:

 $70^{\circ}\text{C} + 0.597\text{W} * 42.1^{\circ}\text{C/W} = 95.1^{\circ}\text{C}$. This is well below the limit of 125°C .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow, and the type of board (single layer or multi-layer).

Table 8A. Thermal Resistance $\theta_{\rm JA}$ for 32-pin LQFP, Forced Convection

θ_{JA} by Velocity (Linear Feet per Minute) 0 200 500 Single-Layer PCB, JEDEC Standard Test Boards 67.8°C/W 55.9°C/W 50.1°C/W Multi-Layer PCB, JEDEC Standard Test Boards 47.9°C/W 42.1°C/W 39.4°C/W NOTE: Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.

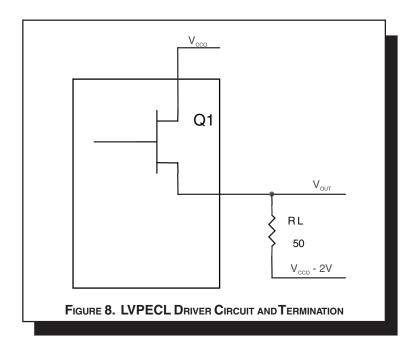
TABLE 8B. THERMAL RESISTANCE θ., FOR 32-PIN VFQFN FORCED CONVECTION

TABLE OB. THERMAL RESISTANCE O _{JA} FOR 32-PIN VFQFN FORCED CONVECTION					
θ _{JA} by Velocity (Linear Feet per Minute)					
0					
34.8C/W					

3. Calculations and Equations.

The purpose of this section is to derive the power dissipated into the load.

LVPECL output driver circuit and termination are shown in Figure 8.



To calculate worst case power dissipation into the load, use the following equations which assume a 50Ω load, and a termination voltage of V_{CCO} - 2V.

• For logic high,
$$V_{OUT} = V_{OH_MAX} = V_{CCO_MAX} - 0.9V$$

$$(V_{CCO_MAX} - V_{OH_MAX}) = 0.9V$$

• For logic low,
$$V_{OUT} = V_{OL_MAX} = V_{CCO_MAX} - 1.7V$$

$$(V_{CCO_MAX} - V_{OL_MAX}) = 1.7V$$

Pd_H is power dissipation when the output drives high. Pd_L is the power dissipation when the output drives low.

$$Pd_H = [(V_{OH_MAX} - (V_{CCO_MAX} - 2V))/R_{L}] * (V_{CCO_MAX} - V_{OH_MAX}) = [(2V - (V_{CCO_MAX} - V_{OH_MAX}))/R_{L}] * (V_{CCO_MAX} - V_{OH_MAX}) = [(2V - 0.9V)/50\Omega) * 0.9V = 19.8mW$$

$$Pd_L = [(V_{OL_MAX} - (V_{CCO_MAX} - 2V))/R_{L}] * (V_{CCO_MAX} - V_{OL_MAX}) = [(2V - (V_{CCO_MAX} - V_{OL_MAX}))/R_{L}] * (V_{CCO_MAX} - V_{OL_MAX}) = [(2V - 1.7V)/50\Omega) * 1.7V = 10.2mW]$$

Total Power Dissipation per output pair = Pd_H + Pd_L = 30mW



780MHz, Crystal-to-3.3V Differential LVPECL Frequency Synthesizer

RELIABILITY INFORMATION

Table 9A. $\theta_{JA} vs.$ Air Flow Table for 32 Lead LQFP

θ_{IA} by Velocity (Linear Feet per Minute)

 0
 200
 500

 Single-Layer PCB, JEDEC Standard Test Boards
 67.8°C/W
 55.9°C/W
 50.1°C/W

 Multi-Layer PCB, JEDEC Standard Test Boards
 47.9°C/W
 42.1°C/W
 39.4°C/W

NOTE: Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.

Table 9B. $\theta_{\text{JA}} \text{vs. Air FlowTable for 32 Lead VFQFN Package}$

θ_{IA} by Velocity (Linear Feet per Minute)

0

Multi-Layer PCB, JEDEC Standard Test Boards 34.8°C/W

TRANSISTOR COUNT

The transistor count for ICS84320-01 is: 3776

PACKAGE OUTLINE - Y SUFFIX FOR 32 LEAD LQFP

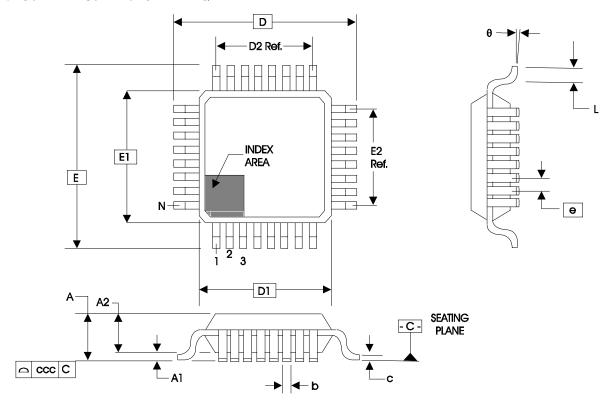


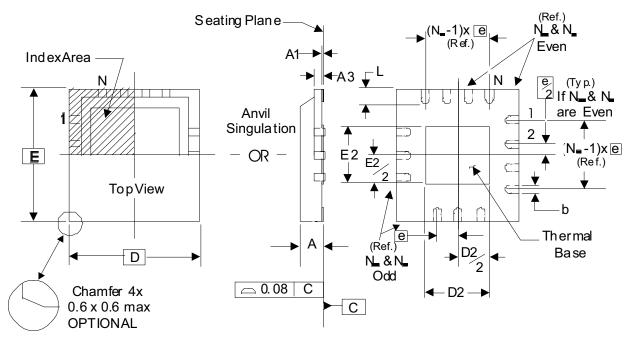
TABLE 10A. PACKAGE DIMENSIONS

JEDEC VARIATION ALL DIMENSIONS IN MILLIMETERS				
0.44501	ВВА			
SYMBOL	MINIMUM	NOMINAL	MAXIMUM	
N	32			
Α			1.60	
A 1	0.05		0.15	
A2	1.35	1.40	1.45	
b	0.30	0.37	0.45	
С	0.09		0.20	
D	9.00 BASIC			
D1	7.00 BASIC			
D2	5.60 Ref.			
E	9.00 BASIC			
E1	7.00 BASIC			
E2	5.60 Ref.			
е	0.80 BASIC			
L	0.45	0.60	0.75	
θ	0°		7°	
ccc	0.10			

Reference Document: JEDEC Publication 95, MS-026



PACKAGE OUTLINE - 32 LEAD K PACKAGE



NOTE: The following package mechanical drawing is a generic drawing that applies to any pin count VFQFN package. This drawing is not intended to convey the actual pin count or pin layout of this device. The pin count and pinout are shown on the front page. The package dimensions are in Table 10B below.

TABLE 10B. PACKAGE DIMENSIONS

JEDEC VARIATION ALL DIMENSIONS IN MILLIMETERS				
SYMBOL	Minimum	Maximum		
N	32			
A	0.80	1.0		
A1	0	0.05		
А3	0.25 Reference			
b	0.18	0.30		
e	0.50 BASIC			
N _D	8			
N _E	8			
D	D 5.0			
D2	1.25	3.25		
E	5.0			
E2	1.25	3.25		
L	0.30	0.50		

Reference Document: JEDEC Publication 95, MO-220



TABLE 11. ORDERING INFORMATION

Part/Order Number	Marking	Package	Shipping Packaging	Temperature	
ICS84320AY-01	ICS84320AY-01	32 Lead LQFP	tray	0°C to 70°C	
ICS84320AY-01T	ICS84320AY-01	32 Lead LQFP	1000 tape & reel	0°C to 70°C	
ICS84320AY-01LN	ICS84320A01N	32 Lead "Lead-Free/Annealed" LQFP	tray	0°C to 70°C	
ICS84320AY-01LNT	ICS84320A01N	32 Lead "Lead-Free/Annealed" LQFP	1000 tape & reel	0°C to 70°C	
ICS84320AK-01	ICS84320AK01	32 Lead VFQFN	tray	0°C to 70°C	
ICS84320AK-01T	ICS84320AK01	32 Lead VFQFN	2500 tape & reel	0°C to 70°C	
ICS84320AK-01LF	ICS4320A01L	32 Lead "Lead-Free" VFQFN	tray	0°C to 70°C	
ICS84320AK-01LFT	ICS4320A01L	32 Lead "Lead-Free" VFQFN	2500 tape & reel	0°C to 70°C	

NOTE: Parts that are ordered with an "LF" or LN" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

While the information presented herein has been checked for both accuracy and reliability, Integrated Device Technology, Incorporated (IDT) assumes no responsibility for either its use or for infringement of any patients or other rights of third parties, which would result from its use. No other circuits, patients, or licenses are implied. This product is intended for use in normal commercial applications. Any other applications such as those requiring extended temperature ranges, high reliability or other extraordinary environmental requirements are not recommended without additional processing by IDT. IDT reserves the right to change any circuitry or specifications without notice. IDT does not authorize or warrant any IDT product for use in life support devices or critical medical instruments.

20 REV.C OCTOBER 22, 2007 84320AY-01



REVISION HISTORY SHEET						
Rev	ev Table Page Description of Change					
Α		7	Updated Typical Phase Noise plots and format.	7/2/04		
Α	T11	16	Ordering Information Table - added Lead Free Part/Order Number.	8/24/04		
В	T4A T6 T11	1 5 6 8 9 10 18	Features Section - added Lead-Free bullet. Power Supply DC Characteristics - updated VCCA min. from 3.135V to V _{CC} - 0.22. Crystal Characteristics Table - added Drive Level. Corrected 3.3V Output Load AC Test Circuit diagram. Added Recommendations for Unused Input and Output Pins. Added LVCMOS to XTAL Interface. Ordering Information Table - added lead-free part number. Added VFQFN package throughout the datasheet.	4/14/06		
С	T4C	6 14 - 15	LVPECL DC Characteristics Table -corrected V_{OH} max. from $V_{CCO} - 1.0V$ to $V_{CCO} - 0.9V$. Power Considerations - corrected power dissipation to reflect V_{OH} max in Table 4C.	4/10/07		
С	T11	14 19	Added VFQFN EPAD Thermal Release Path section. Ordering Information Table - added lead-free marking.	10/22/07		